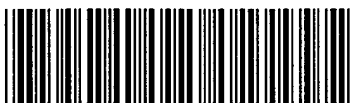


**Search Notes**

Application/Control No.

10/693,288

Examiner

Eric B. Chen

Applicant(s)/Patent under  
Reexamination

LEE, HEON

Art Unit

1765

**SEARCHED**

Class	Subclass	Date	Examiner
216	18,22,38	6/7/2005	EC
216	39,46,67	6/7/2005	EC
438	3,257	6/7/2005	EC
438	710,723	6/7/2005	EC
438	724	6/7/2005	EC
438	692,696	6/7/2005	EC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Performed inventor search for double patenting	6/2/2005	EC
Confirmed search with Anita Alanko	6/7/2005	EC
EAST search	6/7/2005	EC